

E x c o r e m e r e f o n t s i t i o			
Type	Hits	Search Text	DBs
128 BRS	467	multi-beam adj scan\$7	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB
129 BRS	2	(multi-beam adj scan\$7) and surface adj charge	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB
130 BRS	0	("250" and particle adj beam adj inspection) and scan adj control	USPAT
131 BRS	17	"250" and particle adj beam adj inspection	USPAT
132 BRS	221	"250" and wafer adj inspection	USPAT
133 BRS	28	("250" and wafer adj inspection) and particle adj beam	USPAT
134 BRS	59	("250" and wafer adj inspection) and electron adj beam	USPAT
135 BRS	1	"5502306".PN.	USPAT
136 BRS	1	"5122663".PN.	USPAT
137 BRS	1	"5118941".PN.	USPAT

Type	Hits	Search Text	DBs	Time Stamp	△
			USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM TDB	2003/01/28 11:32	0
138	BRS 14	nakasugi-tetsuro.in.	USPAT;		
139	BRS 7	(("250" and wafer adj inspection) and electron adj beam) and scan adj position	USPAT	2003/01/28 14:33	0
140	BRS 1004	250/491.1	USPAT	2003/01/28 14:33	0
141	BRS 5	("3745358" "4807159" "5607801" "5994030" "6388747") .PN.	USPAT	2003/01/28 14:39	0
142	BRS 10	(250/491.1 and insulat\$4 adj film) and alignment adj mark	USPAT;		
143	BRS 948	(250/491.1 and insulat\$4 adj film) alignment adj mark	US-PGPUB	2003/01/28 14:46	0
144	BRS 181	"356" and alignment adj mark) and electron adj beam	USPAT;	2003/01/28 14:47	0
145	BRS 8	(("356" and alignment adj mark) and electron adj beam) and insulat\$4 adj layer	US-PGPUB	2003/01/28 14:48	0
146	BRS 59	250/491.1 and insulat\$4 adj film	USPAT;	2003/01/28 14:51	0
147	BRS 143	250/491.1 and alignment adj mark	USPAT;	2003/01/28 14:51	0
148	BRS 0	((250/491.1 and alignment adj mark) and insulat\$4) and surface adj charg\$4	USPAT;	2003/01/28 14:52	0

Search Text							
Type	Hits	DBs	Time Stamp	△	DBs	Time Stamp	△
149	BRS	36	(250/491.1 and alignment adj mark) and insulat\$4		USPAT; US-PGPUB	2003/01/28 14:53	0
150	BRS	1	5986263.pn.		USPAT	2003/01/28 15:02	0
151	BRS	1	5093572.pn.		USPAT	2003/01/29 11:24	0